Neural Model Checking

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Intro

• LTL verification with proof certificates

proof certificates represented as Neural Networks

verification done on hardware designs

unsupervised / sound / practical

Some Notations

• $X_{\mathcal{M}}$: set of (bit-vector) variables $\{ \begin{array}{l} \cdot & \operatorname{reg} X_{\mathcal{M}} \subseteq X_{\mathcal{M}} & : \operatorname{register} \operatorname{variables} \\ \cdot & \operatorname{inp} X_{\mathcal{M}} \subseteq X_{\mathcal{M}} & : \operatorname{input} \operatorname{variables} \end{array} \}$

- $\operatorname{obs} X_{\mathcal{M}} \subseteq X_{\mathcal{M}}$: observable variables for atomic props in LTL
- $\operatorname{Update}_{\mathcal{M}}$: relation over $X_{\mathcal{M}}$ and $\operatorname{reg} X'_{\mathcal{M}}$
- $oldsymbol{s} \in S$: state (valuation over $X_{\mathcal{M}}$)

Recall: Automata-Theoretic LTL MC

• how to check $\mathcal{M} \models \Phi$?

- 1) build an NBA for $\mathcal{M} \parallel \mathcal{A}_{\neg \Phi}$
 - states of this NBA: (s, q)
- 2) check if final (or fair) states in F can be visited i.o.
 - can -> return false (+ counterexample: lasso)
 - cannot -> return true (+ **proof certificate: ranking function**)

Ranking Functions as Proofs

A ranking function takes a state of the synchronous product as input, and outputs a rank

i.e. ranking function
$$V\colon\operatorname{reg} S imes Q o R$$
 where (R,\prec) : well-founded



Conditions for ranking functions:

$$(s, q) \rightarrow_{\mathcal{M} \parallel \mathcal{A}_{\neg \Phi}} (s', q') \implies V(\operatorname{reg} s, q) \succeq V(\operatorname{reg} s', q')$$
 (1)

$$(s, q) \rightarrow_{\mathcal{M} \parallel \mathcal{A}_{\neg \Phi}} (s', q') \land q \in F \implies V(\operatorname{reg} s, q) \succ V(\operatorname{reg} s', q')$$
 (2)

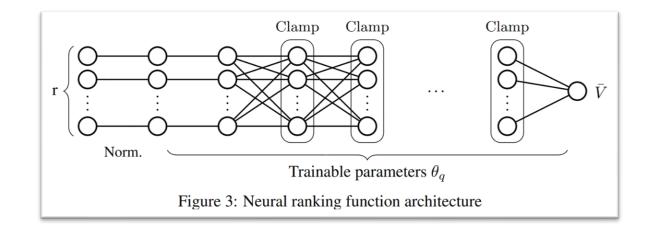
Ranking Functions as NN's

Ranking functions are represented by neural networks:

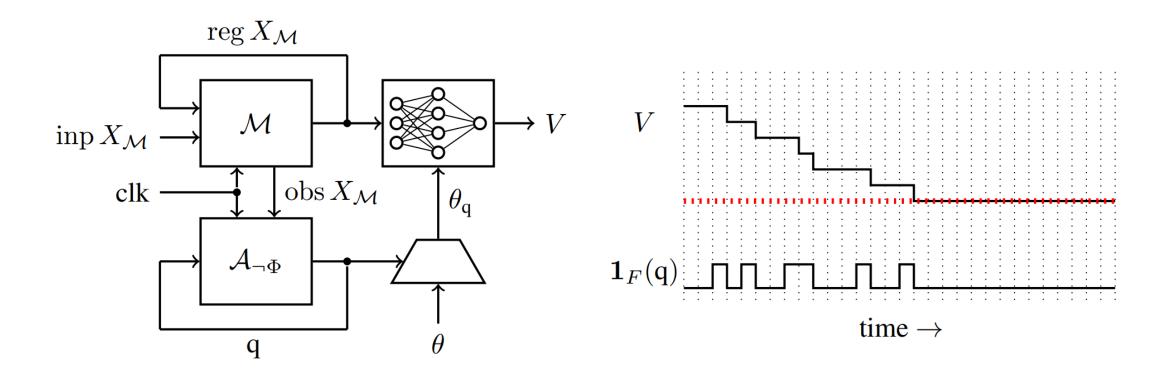
$$V(r,q) \equiv \bar{V}(r;\theta_q)$$

where,

- $\bar{V}: \mathbb{R}^n \times \Theta \to \mathbb{R}$
- $n = |\operatorname{reg} X_{\mathcal{M}}|$

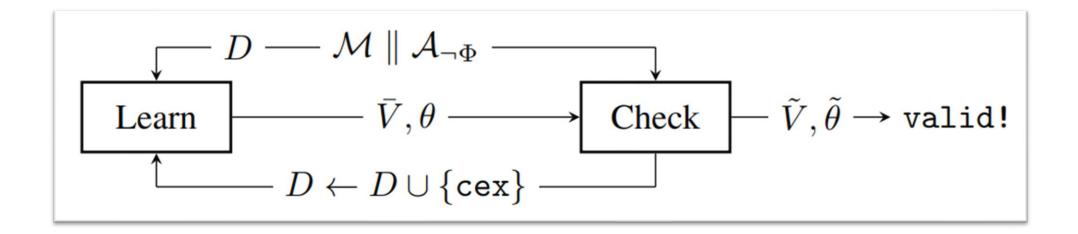


Synchronous Products & Ranking Functions



★ Learn-and-Check Procedure

Task: verify
$$L_{\mathcal{M}}\subseteq L_{\Phi}$$



Learning

To train \bar{V} , for each quadruple $(\boldsymbol{r},\boldsymbol{q},\boldsymbol{r}',\boldsymbol{q}')\in D$, minimize the following:

$$\mathcal{L}_{\text{Rank}}(\boldsymbol{r},\boldsymbol{q},\boldsymbol{r}',\boldsymbol{q}';\boldsymbol{\theta}) = \text{ReLU}(\bar{V}(\boldsymbol{r}';\boldsymbol{\theta}_{\boldsymbol{q}'}) - \bar{V}(\boldsymbol{r};\boldsymbol{\theta}_{\boldsymbol{q}}) + \epsilon \cdot \mathbf{1}_{F}(\boldsymbol{q})).$$

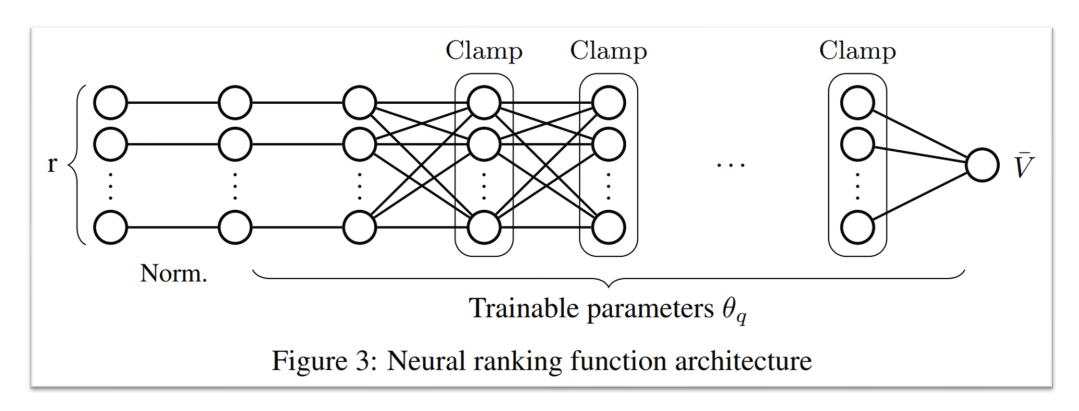
Suppose loss = 0.

- if $q \notin F$, $\bar{V}(r; \theta_q) \geq \bar{V}(r'; \theta_{q'})$
- if ${m q} \in F$, ${ar V}({m r}; {m heta}_{m q}) \geq {ar V}({m r}'; {m heta}_{{m q}'}) + \epsilon$

Overall, the training ensures the following total loss function to take value zero:

$$\mathcal{L}(D;\theta) = \mathbb{E}_{(\boldsymbol{r},\boldsymbol{q},\boldsymbol{r}',\boldsymbol{q}')\in D}[\mathcal{L}_{\text{Rank}}(\boldsymbol{r},\boldsymbol{q},\boldsymbol{r}',\boldsymbol{q}';\theta)]$$

Learning



$$Clamp(x; u) = \max(0, \min(x, u))$$

Learning

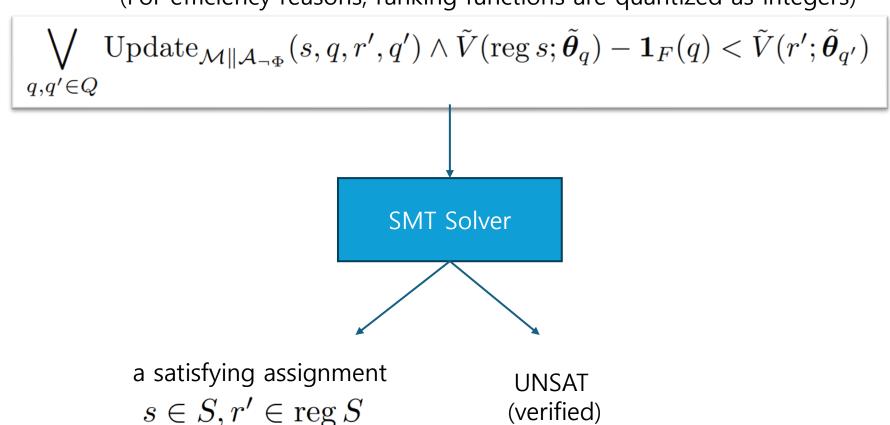
- Suppose training resulted in zero loss
- What do we have?

- Conditions (1) & (2) hold for the dataset D
- But not necessarily for *any* transitions in $\to_{\mathcal{M}\parallel\mathcal{A}_{\neg\Phi}}$

So we need the "checking" phase

Checking

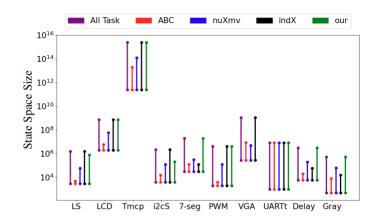
(For efficiency reasons, ranking functions are quantized as integers)

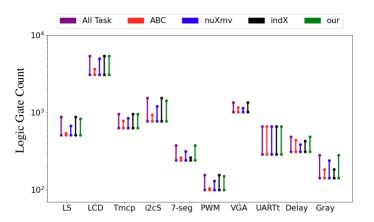


Evaluation

Table 1: Number of verification task completed by academic and industrial tool, per design

							•				_	_
		LS	LCD	Tmcp	i2cS	7-Seg	PWM	VGA	UARTt	Delay	Gray	Total
	Tasks	16	14	17	20	30	12	10	10	32	33	194
	ABC	2	3	7	3	8	2	3	10	6	13	57
•	nuXmv	8	9	12	10	10	7	3	10	24	24	117
	our	15	14	17	18	30	11	0	10	32	33	180
	Ind. X	16	14	17	18	18	12	10	10	19	22	156
	Ind. Y	0	0	0	0	0	0	0	0	0	0	0





* timeout = 5h

Figure 5: Solved tasks in terms of state space size and logic gate count (log scale)